

Supplementary material for:

“Validating classical line profile analyses using microbeam diffraction from individual dislocation cell walls and cell interiors”

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The included plain text files provide the necessary data for reproducing the plots given in Fig. 4 of the main text. The three files are:

“Asymmetric Line Profile” – the X-ray line profile shown in Fig. 4.

“Cell Interior Subprofile” – the cell interior subprofile shown in Fig. 4

“Cell Wall Subprofile” – the cell wall subprofile shown in Fig. 4

The integrated areas under the cell wall and cell interior subprofiles are adjusted as described in the text and shown in Fig. 4. The “Interiors + Wall” profile shown in Fig. 4 may be obtained by summing the cell interior and cell wall subprofiles.